

NBXDBA009

3.3 V, 75 MHz / 150 MHz LVPECL Clock Oscillator

The NBXDBA009 dual frequency crystal oscillator (XO) is designed to meet today's requirements for 3.3 V LVPECL clock generation applications. The device uses a high Q fundamental crystal and Phase Lock Loop (PLL) multiplier to provide selectable 75 MHz or 150 MHz, ultra low jitter and phase noise LVPECL differential output.

This device is a member of ON Semiconductor's PureEdge™ clock family that provides accurate and precision clock solutions.

Available in 5 mm x 7 mm SMD (CLCC) package on 16 mm tape and reel in quantities of 1000.

Features

- LVPECL Differential Output
- Uses High Q Fundamental Mode Crystal and PLL Multiplier
- Ultra Low Jitter and Phase Noise – 0.4 ps (12 kHz – 20 MHz)
- Selectable Output Frequency – 75 MHz (default) / 150 MHz
- Hermetically Sealed Ceramic SMD Package
- RoHS Compliant
- Operating Range 3.3 V $\pm 10\%$
- Total Frequency Stability – ± 50 PPM
- This is a Pb-Free Device

Applications

- SAS Gen2
- Serial ATA

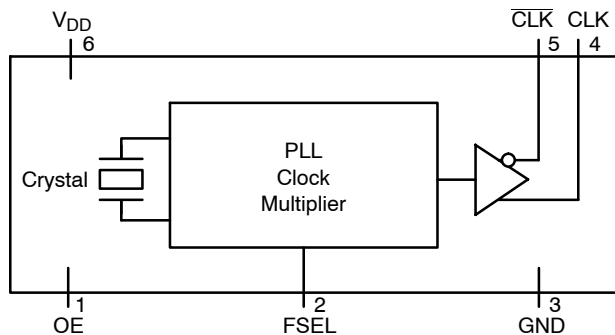
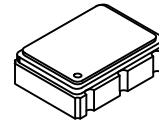


Figure 1. Simplified Logic Diagram



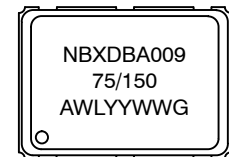
ON Semiconductor®

<http://onsemi.com>



6 PIN CLCC
LN SUFFIX
CASE 848AB

MARKING DIAGRAM



NBXDBA009 = NBXDBA009 (± 50 PPM)
75/150 = Output Frequency (MHz)
A = Assembly Location
WL = Wafer Lot
YY = Year
WW = Work Week
G = Pb-Free Package

ORDERING INFORMATION

Device	Package	Shipping†
NBXDBA009LN1TAG	CLCC-6 (Pb-Free)	1000/ Tape & Reel
NBXDBA009LNHTAG	CLCC-6 (Pb-Free)	100/ Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

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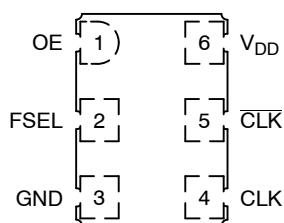


Figure 2. Pin Connections (Top View)

Table 1. PIN DESCRIPTION

Pin No.	Symbol	I/O	Description
1	OE	LVTTTL/LVCMOS Control Input	Output Enable Pin. When left floating pin defaults to logic HIGH and output is active. See OE pin description Table 2.
2	FSEL	LVTTTL/LVCMOS Control Input	Output Frequency Select Pin. Pin will default to logic HIGH when left open. See Output Frequency Select pin description Table 3.
3	GND	Power Supply	Ground 0 V
4	CLK	LVPECL Output	Non-Inverted Clock Output. Typically loaded with 50 Ω receiver termination resistor to $V_{TT} = V_{DD} - 2 V$.
5	$\overline{\text{CLK}}$	LVPECL Output	Inverted Clock Output. Typically loaded with 50 Ω receiver termination resistor to $V_{TT} = V_{DD} - 2 V$.
6	V _{DD}	Power Supply	Positive power supply voltage. Voltage should not exceed 3.3 V \pm 10%.

Table 2. OUTPUT ENABLE TRI-STATE FUNCTION

OE Pin	Output Pins
Open	Active
HIGH Level	Active
LOW Level	High Z

Table 3. OUTPUT FREQUENCY SELECT

FSEL Pin	Output Frequency (MHz)
Open (pin will float high)	75
HIGH Level	75
LOW Level	150

Table 4. ATTRIBUTES

Characteristic	Value
Input Default State Resistor	170 k Ω
ESD Protection	Human Body Model Machine Model 2 kV 200 V
Meets or Exceeds JEDEC Standard EIA/JESD78 IC Latchup Test	

1. For additional Moisture Sensitivity information, refer to Application Note AND8003/D.

Table 5. MAXIMUM RATINGS

Symbol	Parameter	Condition 1	Condition 2	Rating	Units
V _{DD}	Positive Power Supply	GND = 0 V		4.6	V
I _{out}	LVPECL Output Current	Continuous Surge		25 50	mA
T _A	Operating Temperature Range			-40 to +85	$^{\circ}\text{C}$
T _{stg}	Storage Temperature Range			-55 to +120	$^{\circ}\text{C}$
T _{sol}	Wave Solder	See Figure 6		260	$^{\circ}\text{C}$

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

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Table 6. DC CHARACTERISTICS ($V_{DD} = 3.3\text{ V} \pm 10\%$, $GND = 0\text{ V}$, $T_A = -40^\circ\text{C}$ to $+85^\circ\text{C}$) (Note 2)

Symbol	Characteristic	Conditions	Min.	Typ.	Max.	Units
I_{DD}	Power Supply Current			79	100	mA
V_{IH}	OE and FSEL Input HIGH Voltage		2000		V_{DD}	mV
V_{IL}	OE and FSEL Input LOW Voltage		$GND - 300$		800	mV
I_{IH}	Input HIGH Current	OE	-100		+100	μA
		FSEL	-100		+100	
I_{IL}	Input LOW Current	OE	-100		+100	μA
		FSEL	-100		+100	
V_{OH}	Output HIGH Voltage	$V_{DD} = 3.3\text{ V}$	$V_{DD}-1195$ 2105		$V_{DD}-945$ 2355	mV
V_{OL}	Output LOW Voltage	$V_{DD} = 3.3\text{ V}$	$V_{DD}-1945$ 1355		$V_{DD}-1600$ 1700	mV
V_{OUTPP}	Output Voltage Amplitude			660		mV

NOTE: Device will meet the specifications after thermal equilibrium has been established when mounted in a test socket or printed circuit board with maintained transverse airflow greater than 500 lfpm. Electrical parameters are guaranteed only over the declared operating temperature range. Functional operation of the device exceeding these conditions is not implied. Device specification limit values are applied individually under normal operating conditions and not valid simultaneously.

2. Measurement taken with outputs terminated with 50 ohm to $V_{DD}-2\text{ V}$. See Figure 5.

Table 7. AC CHARACTERISTICS ($V_{DD} = 3.3\text{ V} \pm 10\%$, $GND = 0\text{ V}$, $T_A = -40^\circ\text{C}$ to $+85^\circ\text{C}$) (Note 3)

Symbol	Characteristic	Conditions	Min.	Typ.	Max.	Units
f_{CLKOUT}	Output Clock Frequency	FSEL = HIGH		75		MHz
		FSEL = LOW		150		
Δf	Frequency Stability – NBXDBA009	(Note 4)			± 50	ppm
Φ_{NOISE}	Phase-Noise Performance $f_{CLKout} = 75\text{ MHz}/150\text{ MHz}$ (See Figures 3 and 4)	100 Hz of Carrier		-108/-102		dBc/Hz
		1 kHz of Carrier		-122/-116		dBc/Hz
		10 kHz of Carrier		-129/-122		dBc/Hz
		100 kHz of Carrier		-129/-122		dBc/Hz
		1 MHz of Carrier		-137/-131		dBc/Hz
		10 MHz of Carrier		-161/-158		dBc/Hz
$t_{jit}(\Phi)$	RMS Phase Jitter	12 kHz to 20 MHz		0.4	0.9	ps
t_{jitter}	Cycle to Cycle, RMS	1000 Cycles		2.3	8	ps
	Cycle to Cycle, Peak-to-Peak	1000 Cycles		13	30	ps
	Period, RMS	10,000 Cycles		1.3	4	ps
	Period, Peak-to-Peak	10,000 Cycles		8.7	20	ps
$t_{OE/OD}$	Output Enable/Disable Time				200	ns
t_{DUTY_CYCLE}	Output Clock Duty Cycle (Measured at Cross Point)		48	50	52	%
t_R	Output Rise Time (20% and 80%)			250	400	ps
t_F	Output Fall Time (80% and 20%)			250	400	ps
t_{start}	Start-up Time			1	5	ms
	Aging	1 st Year			3	ppm
		Every Year After 1 st			1	ppm

NOTE: Device will meet the specifications after thermal equilibrium has been established when mounted in a test socket or printed circuit board with maintained transverse airflow greater than 500 lfpm. Electrical parameters are guaranteed only over the declared operating temperature range. Functional operation of the device exceeding these conditions is not implied. Device specification limit values are applied individually under normal operating conditions and not valid simultaneously.

3. Measurement taken with outputs terminated with 50 ohm to $V_{DD}-2\text{ V}$. See Figure 5.

4. Parameter guarantees 10 years of aging. Includes initial stability at 25°C, shock, vibration, and first year aging.

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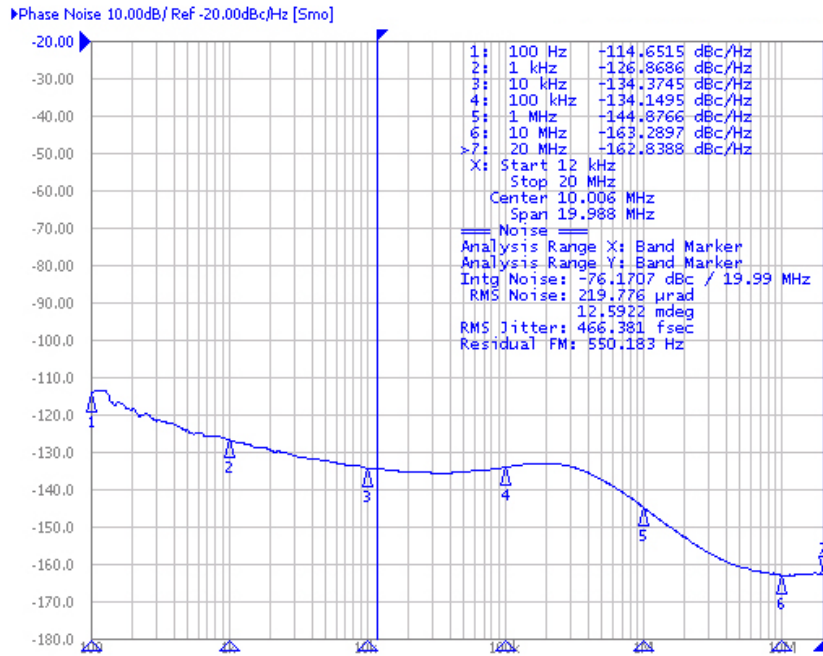


Figure 3. Typical Phase Noise Plot at 75 MHz

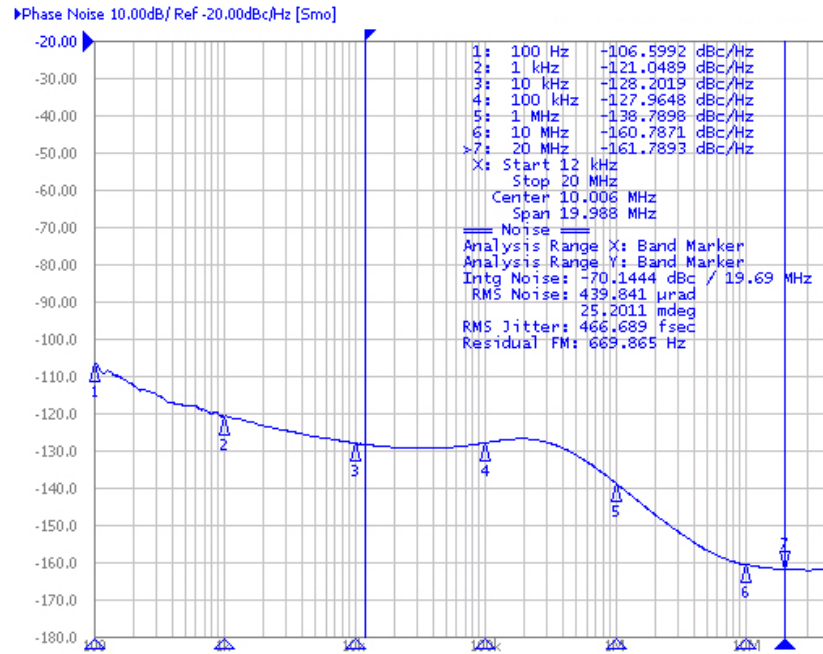


Figure 4. Typical Phase Noise Plot at 150 MHz

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Table 8. RELIABILITY COMPLIANCE

Parameter	Standard	Method
Shock	Mechanical	MIL-STD-833, Method 2002, Condition B
Solderability	Mechanical	MIL-STD-833, Method 2003
Vibration	Mechanical	MIL-STD-833, Method 2007, Condition A
Solvent Resistance	Mechanical	MIL-STD-202, Method 215
Thermal Shock	Environment	MIL-STD-833, Method 1011, Condition A
Moisture Level Sensitivity	Environment	MSL1 260°C per IPC/JEDEC J-STD-020D

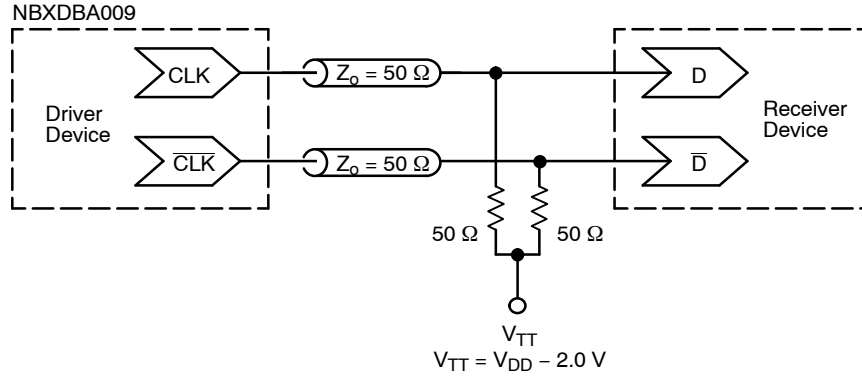


Figure 5. Typical Termination for Output Driver and Device Evaluation (See Application Note AND8020/D – Termination of ECL Logic Devices.)

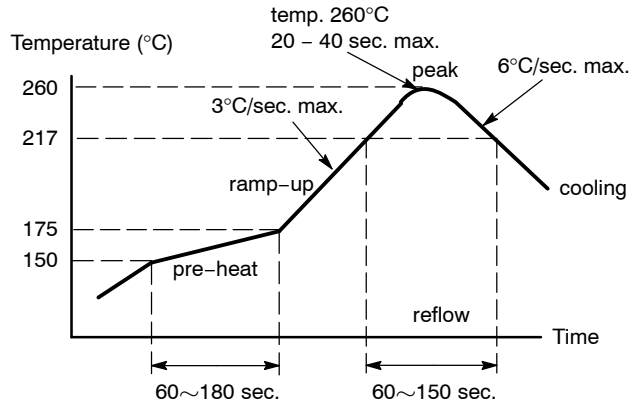


Figure 6. Recommended Reflow Soldering Profile

